

SHORT-FORMAT PAPERS

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Structures of Sulfuryl Halides: SO₂F₂, SO₂ClF and SO₂Cl₂*

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Abstract. Sulfuryl fluoride, SO₂F₂, $M_r = 102.06$, tetragonal, $P4_12_12$, $a = 5.176$ (1), $c = 11.685$ (3) Å, $V = 313.1$ (1) Å³, $Z = 4$, $D_x = 2.17$ Mg m⁻³, Mo $K\alpha$, $\lambda = 0.71073$ Å, $\mu = 0.88$ mm⁻¹, $F(000) = 200$, $T = 126$ K, $R = 0.040$ for 433 unique observed reflections. Sulfuryl chloride fluoride, SO₂ClF, $M_r = 118.51$, orthorhombic, $Pca2_1$, $a = 10.795$ (3), $b = 7.623$ (2), $c = 8.989$ (3) Å, $V = 739.7$ (4) Å³, $Z = 8$, $D_x = 2.13$ Mg m⁻³, Mo $K\alpha$, $\lambda = 0.71073$ Å, $\mu = 1.41$ mm⁻¹, $F(000) = 464$, $T = 123$ K, $R = 0.024$ for 1620 unique reflections. Sulfuryl chloride, SO₂Cl₂, $M_r = 134.97$, orthorhombic, $Fdd2$, $a = 15.425$ (5), $b = 10.336$ (3), $c = 5.422$ (2) Å, $V = 864.4$ (4) Å³, $Z = 8$, $D_x = 2.07$ Mg m⁻³, Mo $K\alpha$, $\lambda = 0.71073$ Å, $\mu = 1.78$ mm⁻¹, $F(000) = 528$, $T = 153$ K, $R = 0.025$ for 510 unique observed reflections. In SO₂F₂ and SO₂Cl₂ the molecules occupy special positions of point symmetry 2. In SO₂ClF two independent molecules in general positions form nearly centrosymmetric pairs. None of the crystal structures of these tetrahedral molecules could be correlated with close sphere packing.

Table 1. Experimental details

	SO ₂ F ₂	SO ₂ ClF	SO ₂ Cl ₂
Range of h	0-8	0-17	-24-24
k	0-5	0-12	-16-16
l	0-18	0-14	0-8
Standard reflections	$\bar{1}\bar{1}5$	$\bar{4}23$	$\bar{5}33$
	$\bar{2}22$	$\bar{4}2\bar{3}$	$\bar{6}4\bar{2}$
	$\bar{2}22$	$\bar{4}33$	$\bar{7}31$
Reflections measured	850	1888	2156
unique	453	1704	513
unobserved ($I < 1.96\sigma_I$)	20	84	3
Parameters refined	24	90	23
R	0.040	0.024	0.025
wR	0.062	0.039	0.044
S	2.581	1.541	2.098
$(\Delta/\sigma)_{\max}$ in final cycle	0.00	0.01	0.00
$(\Delta\rho)_{\min}/(\Delta\rho)_{\max}$, e Å ⁻³	-0.4/0.4	-0.5/0.5	-0.4/0.3

* Part 21 of the series *Fluorides and Fluoro Acids*. Part 20: Pöll, Pawelke, Mootz & Appelman (1988).

Table 2. Atomic coordinates and equivalent isotropic thermal parameters with e.s.d.'s in parentheses

	x	y	z	B_{eq} *(Å ²)
SO ₂ F ₂				
S	0.07889 (9)	x	0	2.76 (1)
F	-0.1101 (3)	-0.0018 (6)	0.0922 (2)	6.83 (8)
O	0.3244 (3)	0.0094 (5)	0.03617 (13)	3.62 (4)
SO ₂ ClF				
S(1)	0.19636 (4)	0.51541 (5)	0.1	1.51 (1)
Cl(1)	0.07414 (4)	0.48657 (6)	-0.06000 (8)	2.27 (1)
F(1)	0.28878 (9)	0.37221 (14)	0.0531 (2)	2.37 (2)
O(11)	0.2577 (2)	0.6771 (2)	0.0837 (2)	2.78 (3)
O(12)	0.1441 (2)	0.4602 (2)	0.2361 (2)	2.45 (3)
S(2)	0.05277 (4)	-0.00531 (5)	0.19169 (5)	1.49 (1)
Cl(2)	0.17932 (4)	0.00504 (6)	0.34836 (8)	2.38 (1)
F(2)	-0.03607 (10)	0.1347 (2)	0.2536 (2)	2.54 (2)
O(21)	-0.0101 (2)	-0.1665 (2)	0.1977 (3)	2.76 (3)
O(22)	0.10285 (14)	0.0620 (2)	0.0585 (2)	2.47 (3)
SO ₂ Cl ₂				
S	0	0	0	2.22 (1)
Cl	0.04546 (3)	0.13224 (5)	-0.23036 (13)	3.50 (1)
O	0.0715 (2)	-0.0551 (2)	0.1261 (6)	5.46 (6)

$$* B_{eq} = \frac{1}{3}(B_{11}a^*a^2 + \dots + B_{23}b^*c^*bccosa).$$

Experimental. Samples of the compounds were sealed in thin-walled capillaries (diameter *ca* 0.2 mm). Single crystals were grown on a Syntex P2₁ four-circle diffractometer equipped with a modified LT-1 low-temperature device. A miniature zone-melting technique using focused heat radiation (Brodalla, Mootz, Boese & Osswald, 1985) was applied for SO₂F₂ and SO₂ClF. A single crystal of SO₂Cl₂ was obtained by slow cooling of the melt. Lattice parameters from setting angles of 15 reflections with $30 < 2\theta < 44^\circ$. Intensities by ω scan with $(\sin\theta)/\lambda$ up to 0.807 Å⁻¹ for each crystal, three standard reflections every 50 data with no significant variations.

Direct methods for SO₂ClF and SO₂Cl₂, heavy-atom method for SO₂F₂. Full-matrix least-squares refinement based on F magnitudes, observed reflections only, weighted according to $w = [\sigma^2(F) + (0.02|F_o|)^2]^{-1}$,

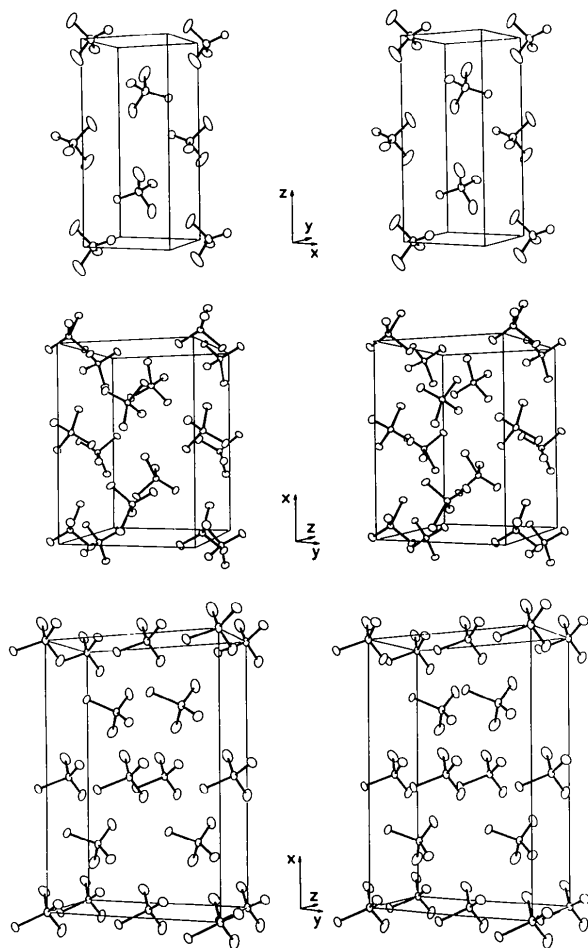


Fig. 1. Stereoplots of the crystal structures. Above: SO_2F_2 ; centre: SO_2ClF ; below: SO_2Cl_2 .

atomic scattering factors from *International Tables for X-ray Crystallography* (1974). Calculations performed using the program systems *XTLE* (Syntex, 1976) and *SHELXTL* (Sheldrick, 1983) on an Eclipse S/200 minicomputer (Data General) and *ORTEPII* (Johnson, 1976) on a TR 445 computer (Telefunken).

Additional experimental details are given in Table 1, the atomic parameters in Table 2, interatomic distances and angles in Table 3.* Fig. 1 shows stereoplots of the crystal structures.

* Lists of structure factors and anisotropic thermal parameters have been deposited with the British Library Document Supply Centre as Supplementary Publication No. SUP 44702 (12 pp.). Copies may be obtained through The Executive Secretary, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

Table 3. *Interatomic distances (Å) and angles (°)*

SO_2F_2			
S—O	1.386 (2)	O—S—O ⁱ	124.63 (11)
S—F	1.514 (2)	O—S—F	107.67 (12)
		O—S—F ⁱ	107.60 (12)
		F—S—F ⁱ	98.62 (13)
SO_2ClF			
S(1)—O(11)	1.407 (2)	S(2)—O(21)	1.4043 (14)
S(1)—O(12)	1.411 (2)	S(2)—O(22)	1.411 (2)
S(1)—Cl(1)	1.9639 (7)	S(2)—Cl(2)	1.9636 (8)
S(1)—F(1)	1.5377 (12)	S(2)—F(2)	1.5388 (13)
O(11)—S(1)—O(12)	122.68 (10)	O(21)—S(2)—O(22)	122.41 (10)
O(11)—S(1)—Cl(1)	109.77 (8)	O(21)—S(2)—Cl(2)	110.10 (8)
O(11)—S(1)—F(1)	106.72 (9)	O(21)—S(2)—F(2)	106.96 (10)
O(12)—S(1)—Cl(1)	109.42 (7)	O(22)—S(2)—Cl(2)	109.12 (7)
O(12)—S(1)—F(1)	106.57 (8)	O(22)—S(2)—F(1)	107.06 (9)
Cl(1)—S(1)—F(1)	98.96 (5)	Cl(2)—S(2)—F(2)	98.43 (6)
SO_2Cl_2			
S—O	1.418 (3)	O—S—O ⁱⁱ	122.4 (2)
S—Cl	1.9799 (6)	O—S—Cl	107.82 (11)
		O—S—Cl ⁱⁱ	107.60 (11)
		Cl—S—Cl ⁱⁱ	101.77 (2)

Symmetry code: (i) $y, x, -z$; (ii) $-x, -y, z$.

Related literature. Molecular geometries from microwave spectroscopy (Lide, Mann & Fristrom, 1957; Holt & Gerry, 1971) and electron diffraction (Hagen, Cross & Hedberg, 1978; Hargittai & Hargittai, 1981).

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